

| | | | | |
|-----------------------------------|--|-------------------------|---|---------------------------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination OHBAYASHI ET AL. | |
| | | 10/773,371 | Examiner | Art Unit Frederick J. Parker |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-4,732,786 | 03-1988 | Patterson et al. | 427/261 |
| | B | US-5,612,281 | 03-1997 | Kobayashi et al. | 428/32.11 |
| | C | US-6,197,381 | 03-2001 | Saito et al. | 427/374.3 |
| | D | US-6,582,802 | 06-2003 | Ohbayashi et al. | 428/206 |
| | E | US-6,685,999 | 02-2004 | Ichinose et al. | 428/32.25 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.